# SILICON-TO-SILICON SOLUTIONS FOR NEXT GEN CONNECTIVITY DEMANDS.



56 Gbps PAM4 (4+4, 8+8), 112 Gbps (x8, 8+8)

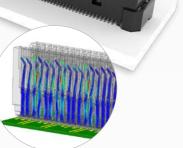


PCI>>

**EXPRESS**®

- Ultra-high pin counts (400 1000+)
- 112 Gbps mezzanine strip
- 5 mm & 10 mm stack heights

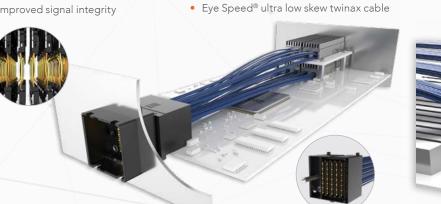
112 Gbps PAM4 High-Speed Edge Card Technology - In Development



# **ExaMAX**®

### High-Performance Backplane Cables

- Two reliable points of contact
- 4 or 6 pairs per column; 4-16 columns
- Increased signal path lengths at higher





### **Extreme Performance / Extreme Density Arrays**

- 4.0 Tbps aggregate data rate
- Extremely low crosstalk
- Tight impedance control
- 0.80 mm pitch terminals / sockets
- 0.80 mm pitch cable assembly
- In Development: right-angle cable mate, 10 mm & 12 mm stack heights, mixed power / single-ended banks, rugged micro backplane system



#### **Extreme Density Bulkhead Cable System** - In Development

- Future-proof design
- High-density, high-performance
- 8, 16, 32 pairs / port



## Double-Density QSFP28 Cable System

- 8 channels, 28 Gbps NRZ / channel
- Direct connect sidebands increase system airflow
- Belly-to-belly mating enables maximum density
- In Development: 112 Gbps PAM4 system



SI-FLY.

Direct Connect to IC Package - In Development

Roadmap: direct connect Optics-to-IC package system

• Ultra high density enables increased channel performance & reach

• 51.2 TB on-package pluggable system

#### Next Gen Extreme Performance Systems - In Development

- Open-pin-field array
- Extreme performance cable assembly



TECHNOLOGIES & SUPPORT FOR NEXT GEN

**SYSTEM DEVELOPMENT & OPTIMIZATION** 

## **Ultra-High Power Micro Systems**

Pair with High-Speed Connectors for Maximum Performance, Density & Power





# Severe Environment Testing (SET)

Samtec interconnects are subject to a wide variety of standard test procedures to help ensure quality and durability in any application.

Severe Environment Testing includes additional testing for interconnect systems that will be used in extreme or harsh environment applications:

- Intense Shock and Vibration: LLCR and Event Detection
- Temperature Cycling (500 Cycles)
- High Mating Cycles with 100% Humidity
  Non-Operating Class Temperature
  - Electrostatic Discharge (ESD)

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